

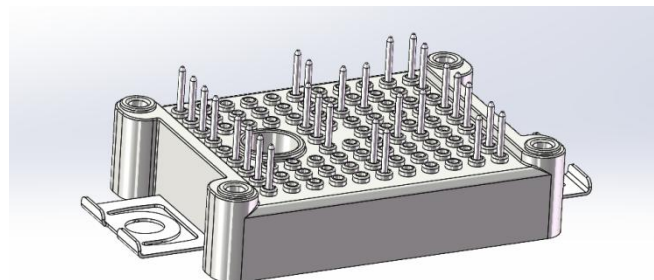
JLCD75B120RE1H7SN

LE1 PACK module with Trench/Fieldstop IGBT and Emitter Controlled diode and NTC



Features

- Low $V_{CE(sat)}$ Trench IGBT technology
- $V_{CE(sat)}$ with positive temperature coefficient
- Maximum junction temperature 175°C
- Low inductance case
- Al_2O_3 substrate with low thermal resistance
- Solder Contact Technology

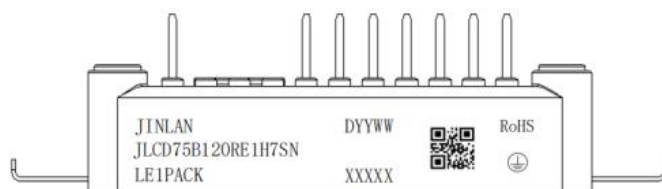


LE1 Pack

MARKING DIAGRAM

Typical Applications

- Air Conditioning
- Motor Drives
- Servo Drives
- UPS Systems
- Auxiliary inverters



JINLAN

JLCD75B120RE1H7SN

YYWW

XXXXX

QR code

= Company Name

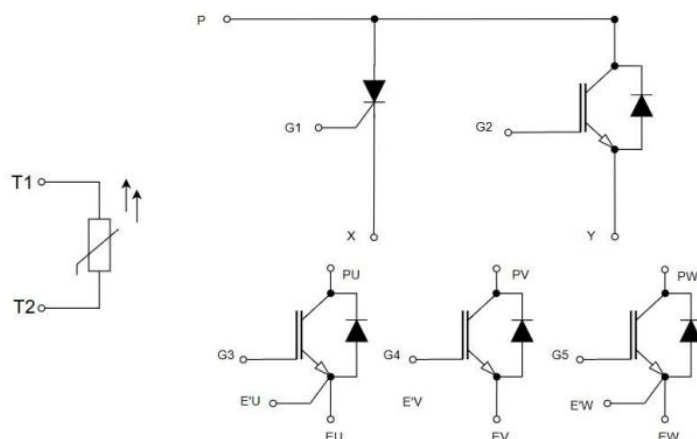
= Specific Device Code

= Year and Work Week Code

= Serial Number

= Custom Assembly

Description





Package Insulation coordination

Parameter	Symbol	Note or test condition	Values	Unit
Isolation test voltage	V_{ISOL}	RMS, $f = 50\text{Hz}$, $t = 60\text{ s}$	2.5	kV
Internal isolation		basic insulation(class 1,IEC 61140)	Al_2O_3	
Creepage distance	d_{creep}	terminal to heatsink	11.5	mm
Creepage distance	d_{creep}	terminal to terminal	6.3	mm
Clearance	d_{clear}	terminal to heatsink	10	mm
Clearance	d_{clear}	terminal to terminal	5	mm
Comparative tracking index (electrical)	CTI		>200	
RTI Elec.	RTI	housing	140	°C

Package Characteristic values

Parameter	Symbol	Note or test condition	Values			Unit
			Min.	Typ.	Max.	
Stray Inductance	L_{CE}		--	25	--	nH
Module Lead Resistance, Terminal to Chip	$R_{CC'+EE'}$		--	4.5	--	mΩ
Storage temperature	T_{stg}		-40	--	125	°C
Mounting force per clamp	F		20	--	50	N
Weight	G		--	24	--	g

**SCR (T1)****Absolute Maximum Ratings** ($T_c = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Description		Value	Unit
V_{DRM}	repetitive peak off-state voltage		1200	V
V_{DSM}	non-repetitive peak off-state voltage		1300	V
V_{RRM}	repetitive peak reverse voltage		1200	V
V_{RSM}	non-repetitive peak reverse voltage		1300	V
$I_{\text{T(AV)}}$	average on-state current	half sine wave	50	A
$I_{\text{T(RMS)}}$	RMS on-state current	half sine wave	79	A
I_{TSM}	non-repetitive peak on-state current	half sine wave; $T_{\text{J(init)}} = 25^\circ\text{C}$; $t_{\text{p}} = 10\text{ ms}$	700	A
		half sine wave; $T_{\text{J(init)}} = 25^\circ\text{C}$; $t_{\text{p}} = 8.3\text{ ms}$	770	
$I^2 t$	$I^2 t$ for fusing	$t_{\text{p}} = 10\text{ ms}$; sine-wave pulse	2450	$\text{A}^2\text{ s}$
di_{T}/dt	rate of rise of on-state current	$I_{\text{G}} = 200\text{ mA}$	150	$\text{A}/\mu\text{s}$
I_{GM}	peak gate current		8	A
V_{GM}	peak gate voltage		5	V
P_{GM}	peak gate power		20	W
$P_{\text{G(AV)}}$	average gate power	over any 20 ms period	1	W

Characteristics ($T_c=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Typ	Max	Unit
I_{GT}	gate trigger current	$V_{\text{D}} = 12\text{ V}$; $I_{\text{T}} = 0.1\text{ A}$; $T_{\text{J}} = 25^\circ\text{C}$	--	--	50	mA
I_{L}	latching current	$V_{\text{D}} = 12\text{ V}$; $I_{\text{G}} = 0.1\text{ A}$; $T_{\text{J}} = 25^\circ\text{C}$	--	--	300	mA
I_{H}	holding current	$V_{\text{D}} = 12\text{ V}$; $T_{\text{J}} = 25^\circ\text{C}$	--	--	200	mA
V_{T}	on-state voltage	$I_{\text{T}} = 50\text{ A}$; $T_{\text{J}} = 25^\circ\text{C}$			1.3	V
		$I_{\text{T}} = 50\text{ A}$; $T_{\text{J}} = 150^\circ\text{C}$			1.2	
V_{o}	threshold voltage	For power-loss calculations only; $T_{\text{J}} = 150^\circ\text{C}$	--	--	975	mV
R_{s}	dynamic resistance		--	--	4.4	m Ω
V_{GT}	gate trigger voltage	$V_{\text{D}} = 12\text{ V}$; $I_{\text{T}} = 0.1\text{ A}$; $T_{\text{J}} = 25^\circ\text{C}$	--	0.7	1	V
		$V_{\text{D}} = 800\text{ V}$; $I_{\text{T}} = 0.1\text{ A}$; $T_{\text{J}} = 125^\circ\text{C}$	0.25	0.4	--	V
I_{D}	off-state current	$V_{\text{D}} = 1200\text{ V}$; $T_{\text{J}} = 25^\circ\text{C}$	--	--	10	μA
		$V_{\text{D}} = 1200\text{ V}$; $T_{\text{J}} = 150^\circ\text{C}$	--	--	5	mA
I_{R}	reverse current	$V_{\text{D}} = 1200\text{ V}$; $T_{\text{J}} = 25^\circ\text{C}$	--	--	10	μA
		$V_{\text{D}} = 1200\text{ V}$; $T_{\text{J}} = 150^\circ\text{C}$	--	--	5	mA
dV_{D}/dt	rate of rise of off-state voltage	$V_{\text{DM}} = 804\text{ V}$; $R_{\text{GK}} = 100\ \Omega$; $T_{\text{J}} = 125^\circ\text{C}$; exponential waveform	1500	--	--	$\text{V}/\mu\text{s}$
		$V_{\text{DM}} = 804\text{ V}$; $R_{\text{GK}} = 100\ \Omega$; $T_{\text{J}} = 150^\circ\text{C}$; exponential waveform	1000	--	--	$\text{V}/\mu\text{s}$
t_{gt}	gate-controlled turn-on time	$I_{\text{TM}} = 40\text{ A}$; $V_{\text{D}} = 800\text{ V}$; $I_{\text{G}} = 0.1\text{ A}$; $di_{\text{G}}/dt = 5\text{ A}/\mu\text{s}$; $T_{\text{J}} = 25^\circ\text{C}$	--	2	--	ns
t_{q}	commutated turn-off time	$V_{\text{DM}} = 804\text{ V}$; $T_{\text{J}} = 125^\circ\text{C}$; $I_{\text{TM}} = 20\text{ A}$; $V_{\text{R}} = 25\text{ V}$; $(di_{\text{T}}/dt)_{\text{M}} = 30\text{ A}/\mu\text{s}$; $dV_{\text{D}}/dt = 50\text{ V}/\mu\text{s}$; $R_{\text{GK(Ext)}} = 100\text{ k}\Omega$; ($V_{\text{DM}} = 67\%$ of V_{DRM})	--	150	--	ns
R_{thJC}	Thermal resistance	Junction-to-Case (per IGBT)	--	0.335	--	K/W
$T_{\text{vj op}}$		Temperature under switching conditions	-40		150 ¹⁾	$^\circ\text{C}$

**IGBT(T2)****Absolute Maximum Ratings** ($T_c = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Description	Value	Unit
V_{CES}	Collector-Emitter Voltage	1200	V
V_{GES}	Gate-Emitter Voltage	± 30	V
I_C	Collector Current @ $T_c=25^\circ\text{C}$	150	A
	Collector Current @ $T_c=100^\circ\text{C}$	75	A
I_{CM}	Pulsed Collector Current, t_p limited by $T_{vj\max}$	225	A
P_{tot}	Total power dissipation, $T_c = 25^\circ\text{C}$, $T_{vj\max} = 175^\circ\text{C}$	355	W

Characteristics ($T_c=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Typ	Max	Unit
$V_{CE(sat)}$	Collector-Emitter Saturation Voltage	$V_{GE} = 15\text{ V}, I_C = 75\text{ A}, T_{vj} = 25^\circ\text{C}$	--	1.65	2.50	V
		$V_{GE} = 15\text{ V}, I_C = 75\text{ A}, T_{vj} = 125^\circ\text{C}$	--	1.75	--	
		$V_{GE} = 15\text{ V}, I_C = 75\text{ A}, T_{vj} = 150^\circ\text{C}$	--	1.85	--	
$V_{GE(TH)}$	Gate-Emitter Threshold Voltage	$I_C = 3\text{ mA}, V_{CE} = V_{GE}$	5.0	6.0	7.0	V
I_{CES}	Collector-Emitter Cutoff Current	$V_{GE} = 0\text{ V}, V_{CE} = 1200\text{ V}$	--	--	100	μA
I_{GES}	Gate-Emitter Leakage Current	$V_{GE} = \pm 30\text{ V}, V_{CE} = 0\text{ V}$	--	--	200	nA
R_{Gint}	Internal Gate Resistance	$f = 1\text{ MHz}$	--	0.5	--	Ω
C_{ies}	Input Capacitance	$V_{CE} = 25\text{ V}, V_{GE} = 0\text{ V},$ $f = 1\text{ MHz}$	--	7.7	--	nF
C_{res}	Reverse Transfer		--	0.04	--	nF
Q_G	Gate Charge	$V_{CE} = 600\text{ V}, I_C = 75\text{ A}$ $V_{GE} = \pm 15\text{ V}$	--	0.36	--	μC
$t_{d(on)}$	Turn-On Delay Time	$V_{CC} = 600\text{ V}, I_C = 75\text{ A}$ $R_{Gon} = 25\Omega, R_{Goff} = 25\Omega$ $V_{GE} = \pm 15\text{ V}$ Inductive Load $T_{vj} = 25^\circ\text{C}$	--	180	--	ns
t_r	Rise Time		--	80	--	
$t_{d(off)}$	Turn-off Delay Time		--	350	--	
t_f	Fall Time		--	210	--	
E_{on}	Turn-On Switching Loss per Pulse		--	15.48	--	mJ
E_{off}	Turn Off Switching Loss per Pulse		--	5.75	--	
$t_{d(on)}$	Turn-On Delay Time	$V_{CC} = 600\text{ V}, I_C = 75\text{ A}$ $R_{Gon} = 25\Omega, R_{Goff} = 25\Omega$ $V_{GE} = \pm 15\text{ V}$ Inductive Load $T_{vj} = 100^\circ\text{C}$	--	180	--	ns
t_r	Rise Time		--	80	--	
$t_{d(off)}$	Turn-off Delay Time		--	390	--	
t_f	Fall Time		--	250	--	
E_{on}	Turn-On Switching Loss per Pulse		--	17.54	--	mJ
E_{off}	Turn Off Switching Loss per Pulse		--	6.77	--	
$I_{C(sc)}$	SC Data	$t_p \leq 10\text{ }\mu\text{s}, V_{GE} \leq 15\text{ V}$ $T_{vj} \leq 150^\circ\text{C}, V_{CC} = 800\text{ V}$ $V_{CEmax} = V_{CES} - L_{sCE} \cdot di/dt$	--	330	--	A
R_{thJC}	Thermal resistance	Junction-to-Case (per IGBT)		0.31		K/W
$T_{vj\text{ op}}$		Temperature under switching conditions	-40		175 ¹⁾	$^\circ\text{C}$

¹⁾ $T_{vj\text{ op}} > 150^\circ\text{C}$ is only allowed for operation at overload conditions.

**Diode(D2)****Absolute Maximum Ratings** (T_c = 25°C unless otherwise noted)

Symbol	Description	Value	Unit
V _{RRM}	Repetitive Peak Reverse Voltage	1200	V
I _F	Diode Continuous Forward Current	75	A
I _{FM}	Diode Maximum Forward Current t _p =1ms	225	A

Characteristics (T_c=25°C unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Typ	Max	Unit
V _F	Diode Forward Voltage	I _F = 75 A, V _{GE} = 0 V, T _{vj} = 25°C	--	2.10	2.90	V
		I _F = 75 A, V _{GE} =0 V, T _{vj} =125°C	--	1.90	--	
		I _F = 75A, V _{GE} = 0 V, T _{vj} = 175°C	--	1.80	--	
Q _r	Recovered Charge	V _R = 600 V, I _F = 75 A V _{GE} = -15 V T _{vj} =25 °C	--	2.31	--	μC
I _{RM}	Peak Reverse Recovery Current		--	35.7	--	A
T _{rr}	Reverse Recovery Time		--	680	--	ns
E _{rec}	Reverse Recovery Energy		--	3.12	--	mJ
Q _r	Recovered Charge	V _R = 600 V, I _F = 75 A V _{GE} = -15 V T _{vj} =100 °C	--	2.56	--	μC
I _{RM}	Peak Reverse Recovery Current		--	37.8	--	A
T _{rr}	Reverse Recovery Time		--	850	--	ns
E _{rec}	Reverse Recovery Energy		--	4.77	--	mJ
R _{thJC}	Thermal resistance	Junction-to-Case (per diode)	--	0.59	--	K/W
T _{vj op}	Temperature under switching conditions		-40	--	175 ²⁾	°C

²⁾T_{vj op} > 150°C is only allowed for operation at overload conditions.

**IGBT(T3,T4,T5)****Absolute Maximum Ratings** ($T_c = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Description	Value	Unit
V_{CES}	Collector-Emitter Voltage	1200	V
V_{GES}	Gate-Emitter Voltage	± 30	V
I_{CDC}	Collector Current @ $T_c=25^\circ\text{C}$	70	A
	Collector Current @ $T_c=100^\circ\text{C}$	35	A
I_{CM}	Pulsed Collector Current, t_p limited by $T_{vj\max}$	70	A
P_D	Power Dissipation @ $T_c = 25^\circ\text{C}$	258	W
	Power Dissipation @ $T_c = 100^\circ\text{C}$	129	W

Characteristics ($T_c=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Typ	Max	Unit
$V_{CE(sat)}$	Collector-Emitter Saturation Voltage	$V_{GE} = 15\text{ V}, I_C = 35\text{ A}, T_{vj} = 25^\circ\text{C}$	--	1.60	2.10	V
		$V_{GE} = 15\text{ V}, I_C = 35\text{ A}, T_{vj} = 125^\circ\text{C}$	--	1.75	--	
		$V_{GE} = 15\text{ V}, I_C = 35\text{ A}, T_{vj} = 150^\circ\text{C}$	--	1.80	--	
$V_{GE(TH)}$	Gate-Emitter Threshold Voltage	$V_{GE} = V_{CE}, I_C = 1\text{ mA}, T_{vj} = 25^\circ\text{C}$	5.0	6.0	7.0	V
I_{CES}	Collector-Emitter Cutoff Current	$V_{GE} = 0\text{ V}, V_{CE} = V_{CES}, T_{vj} = 25^\circ\text{C}$	--	--	200	μA
I_{GES}	Gate-Emitter Leakage Current	$V_{GE} = V_{GES}, V_{CE} = 0\text{ V}, T_{vj} = 25^\circ\text{C}$	--	--	200	nA
R_{Gint}	Internal Gate Resistance	$f=1\text{MHz}$	--	1.34	--	Ω
C_{ies}	Input Capacitance	$V_{CE}=25\text{V}, f=1\text{MHz},$ $V_{GE}=0\text{V}$	--	4140	--	pF
C_{res}	Reverse Transfer		--	36.5	--	pF
Q_G	Gate Charge	$V_{GE} = 15\text{ V}, I_C=35\text{A}$	--	0.15	--	μC
$t_{d(on)}$	Turn-On Delay Time	$V_{CE} = 600\text{ V}, I_C = 35\text{ A},$ $R_G = 10\Omega, V_{GE(on)} = 15\text{ V}, V_{GE(off)} = -5\text{ V},$ $T_{vj} = 25^\circ\text{C}$	--	90	--	ns
t_r	Rise Time		--	216	--	
$t_{d(off)}$	Turn-off Delay Time		--	176	--	
t_f	Fall Time		--	92	--	
E_{on}	Turn-On Switching Loss per Pulse		--	1.83	--	mJ
E_{off}	Turn Off Switching Loss per Pulse		--	2.55	--	
$t_{d(on)}$	Turn-On Delay Time	$V_{CE} = 600\text{ V}, I_C = 35\text{ A},$ $R_G = 10\Omega, V_{GE(on)} = 15\text{ V}, V_{GE(off)} = -5\text{ V},$ $T_{vj} = 150^\circ\text{C}$	--	95	--	ns
t_r	Rise Time		--	264	--	
$t_{d(off)}$	Turn-off Delay Time		--	212	--	
t_f	Fall Time		--	163	--	
E_{on}	Turn-on Switching Loss per Pulse		--	2.65	--	mJ
E_{off}	Turn Off Switching Loss per Pulse		--	3.68	--	
I_{sc}	Short circuit collector current	$t_p \leq 10\mu\text{s}, V_{GE} = 15\text{ V},$ $T_{vj} = 150^\circ\text{C}, V_{CC} \leq 800\text{ V},$	--	110	--	A
T_{sc}	Short circuit time	$V_{GE} = 16\text{ V},$ $T_{vj} = 150^\circ\text{C}, V_{CC} \leq 800\text{ V}$	6	--	--	μS
R_{thJC}	Thermal resistance	Junction-to-Case (per IGBT)	--	0.58		K/W
$T_{vj\text{ op}}$	Temperature under switching conditions		-40	--	175 ³⁾	$^\circ\text{C}$

³⁾ $T_{vj\text{ op}} > 150^\circ\text{C}$ is only allowed for operation at overload conditions.

**Diode(D3,D4,D5)****Absolute Maximum Ratings** ($T_c = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Description	Value	Unit
V_{RRM}	Repetitive Peak Reverse Voltage	1200	V
I_F	Diode Continuous Forward Current	35	A
I_{FM}	Diode Maximum Forward Current $t_p=1\text{ms}$	70	A

Characteristics ($T_c=25^\circ\text{C}$ unless otherwise noted)

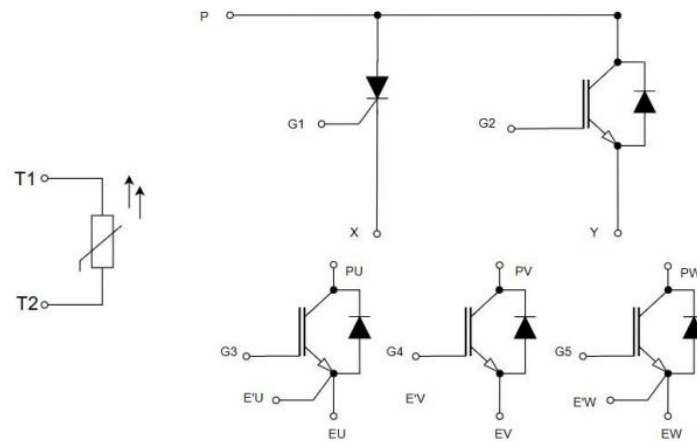
Symbol	Parameter	Test Condition	Min	Typ	Max	Unit
V_F	Diode Forward Voltage	$I_F = 35\text{A}, V_{GE}=0\text{V}, T_{vj} = 25^\circ\text{C}$	--	1.60	2.60	V
		$I_F = 35\text{A}, V_{GE}=0\text{V}, T_{vj} = 125^\circ\text{C}$	--	1.55	--	
		$I_F = 35\text{A}, V_{GE}=0\text{V}, T_{vj} = 150^\circ\text{C}$	--	1.50	--	
Q_r	Recovered Charge	$V_R=600\text{V}, I_F=35\text{A},$ $R_G = 10\Omega, V_{GE(on)} = 15\text{V}, V_{GE(off)} = -5\text{V},$ $T_{vj}=25^\circ\text{C}$	--	0.65	--	μC
I_{RM}	Peak Reverse Recovery Current		--	38	--	A
T_{rr}	Reverse Recovery Time		--	25	--	ns
E_{rec}	Reverse Recovery Energy		--	0.7	--	mJ
Q_r	Recovered Charge	$V_R=600\text{V}, I_F=35\text{A},$ $R_G = 10\Omega, V_{GE(on)} = 15\text{V}, V_{GE(off)} = -5\text{V},$ $T_{vj}=150^\circ\text{C}$	--	1.14	--	μC
I_{RM}	Peak Reverse Recovery Current		--	39	--	A
T_{rr}	Reverse Recovery Time		--	40	--	ns
E_{rec}	Reverse Recovery Energy		--	1.55	--	mJ
R_{thJC}	Thermal resistance	Junction-to-Case (per diode)	--	0.81	--	K/W
$T_{vj\text{ op}}$	Temperature under switching conditions		-40	--	175 ⁴⁾	$^\circ\text{C}$

⁴⁾ $T_{vj\text{ op}} > 150^\circ\text{C}$ is only allowed for operation at overload conditions.

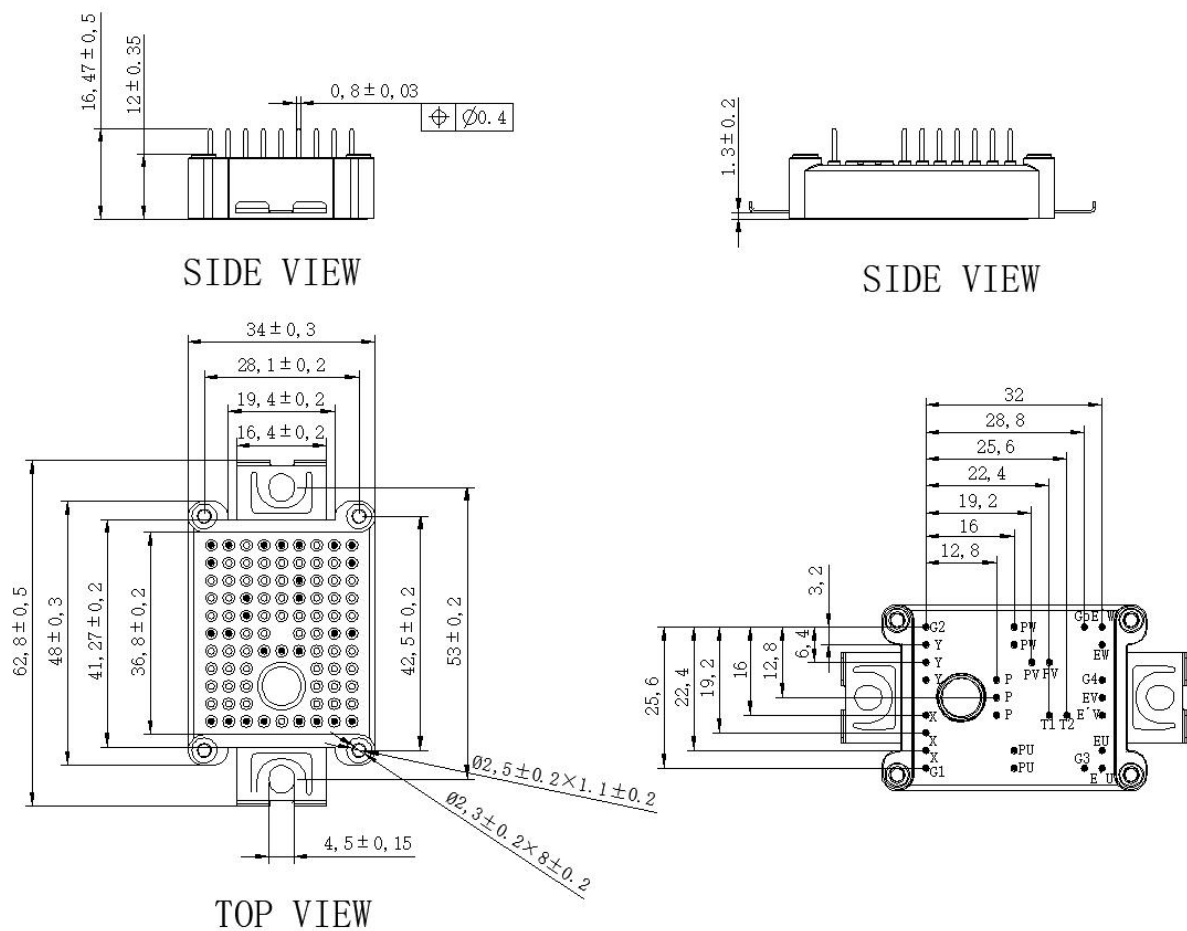
NTC Characteristics ($T_c = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Typ	Max	Unit
R_{25}	Rated Resistance		--	5.0	--	k Ω
$\Delta R/R$	Deviation of R100	$T_c=100^\circ\text{C}, R_{100}=493.3\Omega$	-5	--	5	%
P_{25}	Power Dissipation		--	--	20.0	mW
$B_{25/50}$	B-value	$R_2=R_{25}\exp[B_{25/50}(1/T_2 - 1/(298.15\text{K}))]$	--	3375	--	K
$B_{25/80}$	B-value	$R_2=R_{25}\exp[B_{25/80}(1/T_2 - 1/(298.15\text{K}))]$	--	3411	--	K
$B_{25/100}$	B-value	$R_2=R_{25}\exp[B_{25/100}(1/T_2 - 1/(298.15\text{K}))]$	--	3433	--	K

CIRCUIT DIAGRAM



PACKAGE DIMENSION





REVISION HISTORY

Document version	Date of release	Description of changes
Rev.00	2025-03-10	Preview



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